Search Notes

Application/Control No.							

Applicant(s)/Patent under Reexamination

10/761,080 Examiner

Binh X. Tran

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Art Unit

1765

SEARCHED					
Class	Subclass	Date	Examiner		
216	84	9/26/2006	ВТ		
216	85	9/26/2006	вт		
216	92	9/26/2006	ВТ		
216	97	9/26/2006	ВТ		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
216	84	9/26/2006	ВТ	
216	85	9/26/2006	ВТ	
216	92	9/26/2006	ВТ	
216/97		9/26/2006	вт	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Updated search using USPAT, USPG- PUB, JPO, EPO, DERWENT databases	9/26/2006	ВТ	
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